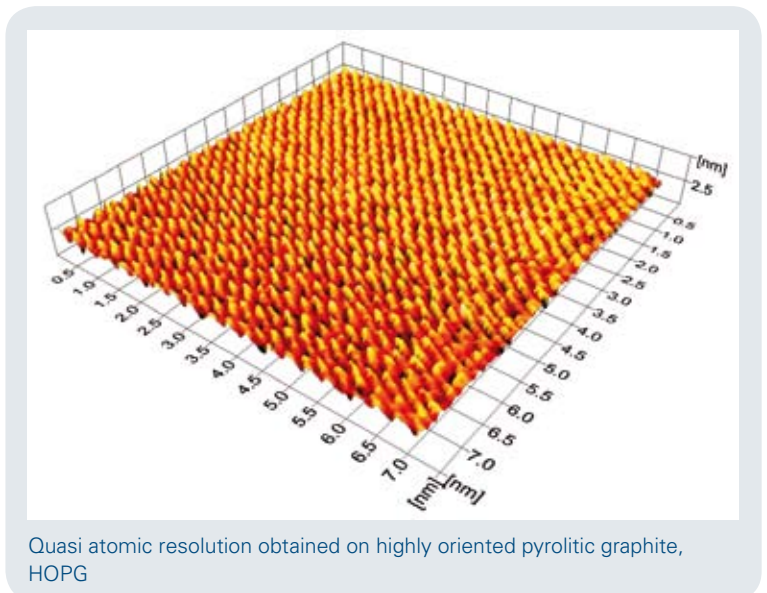
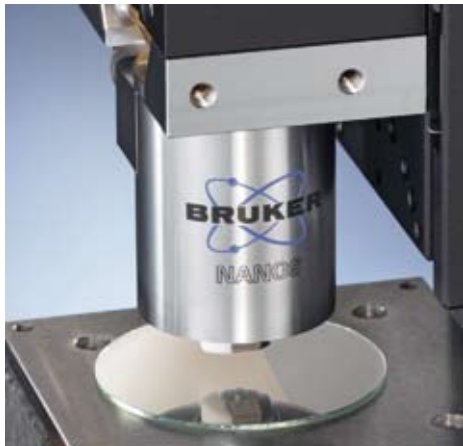


● **N8 ARGOS** AFM/SPM

Simple and precise scanning probe microscopy

The compact N8 ARGOS consists of a unique, sturdy mounting combined with the versatile NANOS scanning probe microscope head. It is just as flexible as its big sister, the N8 NEOS. Either as a complete initial system or as an accessory for your optical microscope, make the most of your NANOS and turn it into a high-resolution scanning probe microscope. The solid and very stable mounting of granite permits familiar, user-friendly handling. The great stability means that a noise level of below 0.05 nm RMS can be achieved (in connection with the optional active antivibration system). This extremely low noise level means that atomic corrugations can be seen with no difficulty.





Detail of the N8 ARGOS, with the NANOS measuring head

Measuring modes

The NANOS offers maximum versatility. All SPM measuring modes can be used, and the system can be easily adapted to new applications. The following standard measuring modes are available: contact, non-contact mode, intermittent contact mode, phase contrast, field contrast for magnetic or electrical characterizations (MFM/EFM), force modulation (FM), lateral force (LFM), Scanning Surface Potential (SSPM), Spreading Resistance (SR), fluid compatibility, metrology-compatible measuring head with sensor. Other modes are available on request.

Applications

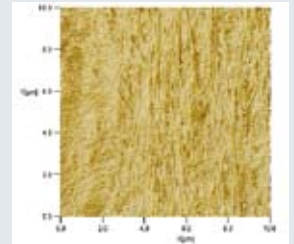
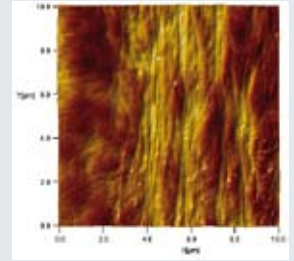
The N8 ARGOS can be used to inspect all biological or inorganic surfaces.

N8 ARGOS Specifications

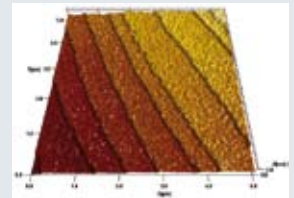
Scan range:	20 μm x 20 μm x 3 μm 40 μm x 40 μm x 4 μm 80 μm x 80 μm x 6 μm hardware linearized scan motion in X-Y- direction (optionally in Z-direction)
Noise level:	0.05 nm RMS in vertical direction (Z)
Lateral accuracy:	typically within 1%, closed loop scanning
Scan speed:	typ. 1 to 10 Hz
Detection principle:	fiber optical interferometry, noise level < 0.01 nm RMS
Tips:	silicon tips, various types
Tip change:	adjustment free
Digital input res.:	16 bit A/D
Digital output res.:	16 bit D/A
Output voltage:	± 165 V, mit 2mV RMS
Input channels:	max. 8 simultaneously
External inputs:	max. 3 with 16 bit resolution
Image size:	freely selectable, from 128 to 1024 pixels
Processing:	internal 32 bit DSP, typ. 50 MHz
PC interface:	USB (standard universal serial bus)
OS:	MS-Windows XP® MS-Windows Vista®

including high resolution stepper motor
for automatic sample approach

Applications



Polymer surface
top image: topography
bottom image: phase image
acquired simultaneously



3D image of mono atomic
terraces on Si 111

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